

Search Notes**Application/Control No.**

10/781,699

Examiner

Y. J. Han

Applicant(s)/Patent under Reexamination

EGUCHI ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
363	16		
	17		
	21.01		
	65		
	68		
	71		
	75		
	98		
	132	8/05	g/t
Search	updated	1/06	g/t

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner